

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links**

» S

Welcome to IEEE Xplore®

- Home
- What Can I Access?
- Log-out

Tables of Contents

- Journals & Magazines
- Conference Proceedings
- Standards

Search

- By Author
- Basic
- Advanced

Member Services

- Join IEEE
- Establish IEEE Web Account

Print Format

Your search matched **28** of **794619** documents.Results are shown **15** to a page, sorted by **publication year in descending order**.You may refine your search by editing the current search expression or entering a new one the text box
Then click **Search Again**.

((((random)and (generate)) and(seed)) and ((1988 <in>))

Search Again**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Accumulator based deterministic BIST***Dorsch, R.; Wunderlich, H.-J.*

Test Conference, 1998. Proceedings., International , 1998

Page(s): 412 -421

[\[Abstract\]](#) [\[PDF Full-Text \(652 KB\)\]](#) **CNF****2 An algorithmic approach to optimizing fault coverage for BIST logic synthesis***Devadas, S.; Keutzer, K.*

Test Conference, 1998. Proceedings., International , 1998

Page(s): 164 -173

[\[Abstract\]](#) [\[PDF Full-Text \(880 KB\)\]](#) **CNF****3 BETSY: synthesizing circuits for a specified BIST environment***Zhe Zhao; Pouya, B.; Touba, N.A.*

Test Conference, 1998. Proceedings., International , 1998

Page(s): 144 -153

[\[Abstract\]](#) [\[PDF Full-Text \(784 KB\)\]](#) **CNF****4 A pseudorandom test environment***Beckwith, R.F.; Wood, B.; Rioux, B.; Singer, B.*

Verilog HDL Conference and VHDL International Users Forum, 1998. IVC/VIU Proceedings., 1998 International , 1998

Page(s): 153 -157

[Abstract] [PDF Full-Text (20 KB)] **CNF**

5 3D modeling of instabilities in multi-wire Z pinches

Hail, T.A.; Desjarlais, M.P.; Marder, B.M.; Robinson, A.C.

Plasma Science, 1998. 25th Anniversary. IEEE Conference Record - Abstracts
IEEE International on , 1998

Page(s): 318

[Abstract] [PDF Full-Text (92 KB)] **CNF**

**6 Gauss-elimination-based generation of multiple seed-polynomial p
LFSR**

Li-Ren Huang; Jing-Yang Jou; Sy-Yen Kuo

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction
Volume: 16 Issue: 9 , Sept. 1997

Page(s): 1015 -1024

[Abstract] [PDF Full-Text (228 KB)] **JNL**

7 Hierarchical supervisors for automatic detection of software failure

Savor, T.; Seviora, R.E.

Software Reliability Engineering, 1997. Proceedings., The Eighth Internationa
Symposium on , 1997

Page(s): 48 -59

[Abstract] [PDF Full-Text (848 KB)] **CNF**

8 An efficient PRPG strategy by utilizing essential faults

Li-Ren Huang; Jing-Yang Jou; Sy-Yen Kuo

Test Symposium, 1996., Proceedings of the Fifth Asian , 1996

Page(s): 199 -204

[Abstract] [PDF Full-Text (612 KB)] **CNF**

9 Pseudo-periodic 1/f-like noise

Evangelista, G.

Time-Frequency and Time-Scale Analysis, 1996., Proceedings of the IEEE-SP
International Symposium on , 1996

Page(s): 121 -124

[Abstract] [PDF Full-Text (300 KB)] **CNF**

10 Test embedding with discrete logarithms

Lempel, M.; Gupta, S.K.; Breuer, M.A.

Computer-Aided Design of Integrated Circuits and Systems, IEEE Transaction

Volume: 14 Issue: 5 , May 1995

Page(s): 554 -566

[Abstract] [PDF Full-Text (1284 KB)] **JNL**

11 Probabilistic encryption key exchange

Moreau, T.

Electronics Letters , Volume: 31 Issue: 25 , 7 Dec. 1995

Page(s): 2166 -2168

[Abstract] [PDF Full-Text (384 KB)] **JNL**

12 A single chip video signal processing architecture for image processing, and computer vision

Goodenough, J.; Meacham, R.J.; Morris, J.D.; Luke Seed, N.; Ivey, P.A.

Circuits and Systems for Video Technology, IEEE Transactions on , Volume: 5
5 , Oct. 1995

Page(s): 436 -445

[Abstract] [PDF Full-Text (1056 KB)] **JNL**

13 Built-in test for circuits with scan based on reseeding of multiple-polynomial linear feedback shift registers

Hellebrand, S.; Rajski, J.; Tarnick, S.; Venkataraman, S.; Courtois, B.

Computers, IEEE Transactions on , Volume: 44 Issue: 2 , Feb. 1995

Page(s): 223 -233

[Abstract] [PDF Full-Text (1012 KB)] **JNL**

14 On reachability and reverse reachability analysis of communication state machines

Wuxu Peng; Makki, K.

Computer Communications and Networks, 1995. Proceedings., Fourth International Conference on , 1995

Page(s): 58 -65

[Abstract] [PDF Full-Text (632 KB)] **CNF**

15 Decompression of test data using variable-length seed LFSRs

Zacharia, N.; Rajska, J.; Tyszer, J.

VLSI Test Symposium, 1995. Proceedings., 13th IEEE , 1995

Page(s): 426 -433

[Abstract] [PDF Full-Text (612 KB)] **CNF**

1 2 [Next]

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2002 IEEE — All rights reserved